



Class	Subclass	ISSUE CLASSIFICATION

PATENT NUMBER

U.S. UTILITY Patent Application

O.I.P.E.

PATENT DATE

SCANNED

Q.A.

APPLICATION NO. 09/659211	CONT/PRIOR F	CLASS 438	SUBCLASS 650	ART UNIT 2812 2825	EXAMINER Everhart
------------------------------	-----------------	--------------	-----------------	--------------------------	----------------------

Noriyuki Hirayamagi

Alignment-mark detection methods and devices for charged-particle-beam microlithography, and microelectronic-device manufacturing methods comprising same

PTO-2040
12/89

ISSUING CLASSIFICATION

Continued on Issue Slip Inside File Jacket

<input type="checkbox"/> TERMINAL DISCLAIMER	DRAWINGS			CLAIMS ALLOWED	
	Sheets Drwg.	Figs. Drwg.	Print Fig.	Total Claims	Print Claim for O.G.
<input type="checkbox"/> The term of this patent subsequent to _____ (date) has been disclaimed.				NOTICE OF ALLOWANCE MAILED	
	(Assistant Examiner) _____ (Date)				
<input type="checkbox"/> The term of this patent shall not extend beyond the expiration date of U.S Patent No. _____				ISSUE FEE	
	(Primary Examiner) _____ (Date)			Amount Due	Date Paid
<input type="checkbox"/> The terminal _____ months of this patent have been disclaimed.				ISSUE BATCH NUMBER	

WARNING-

WARNING: The information disclosed herein may be restricted. Unauthorized disclosure may be prohibited by the United States Code Title 35, Sections 122, 181 and 368. Possession outside the U.S. Patent & Trademark Office is restricted to authorized employees and contractors only.

Form PTO-436A
(Rev. 6/99)

FILED WITH: DISK (CRF) FICHE CD-ROM

(Attached in pocket on right inside flap)

(FACE)

BEST AVAILABLE COPY